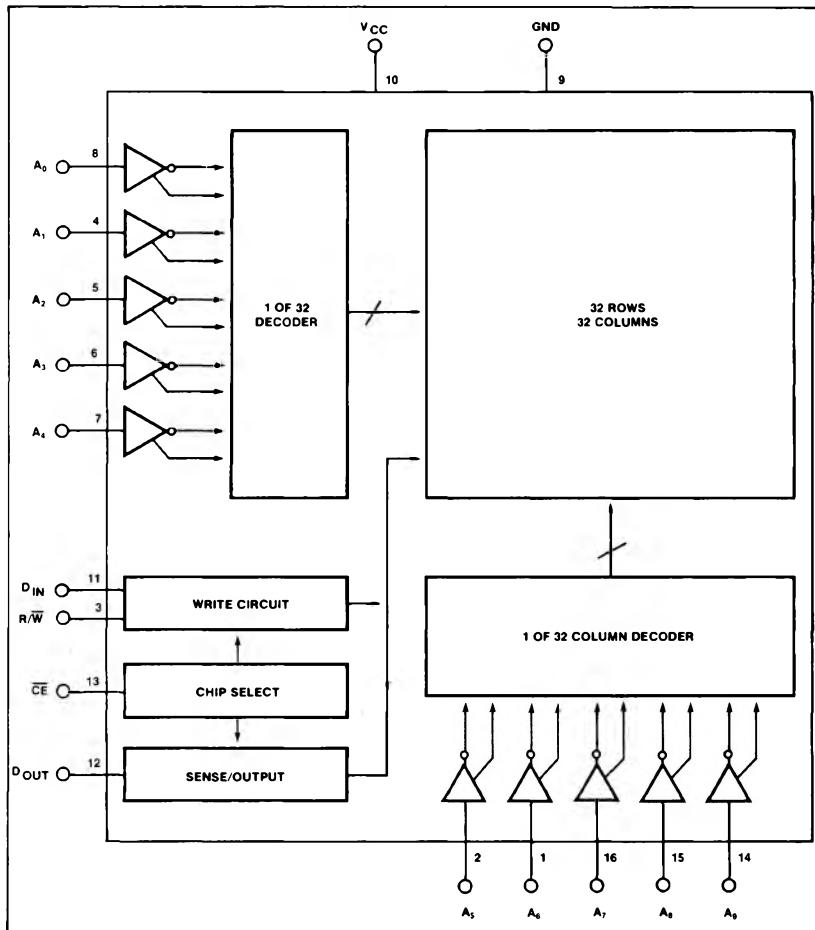
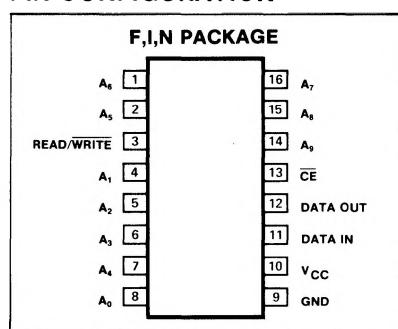


DESCRIPTION

The 2102, 2102-1 and 2102-2 are static random access read/write memories fabricated with low threshold n-channel silicon gate technology.

FEATURES

- Fully static
- Require no clocks
- Completely DTL/TTL compatible
- Single 5V power supply
- Three-state output for OR-tie capability

BLOCK DIAGRAM**PIN CONFIGURATION****ABSOLUTE MAXIMUM RATINGS¹**

PARAMETER	RATING	UNIT
T _{STG}	-65 to 150	°C
P _D		
Temperature range		
Storage	640	mW
Power dissipation ²		
N package	1	W
F package	1	W
I package	-0.5 to 7	V
All input, output and supply voltages with respect to ground		

1024-BIT READ/WRITE STATIC MOS RAM (1024X1)

2102/2102-1/2102-2

2102-F,I,N • 2102-1-F,I,N • 2102-2-F,I,N

DC ELECTRICAL CHARACTERISTICS $T_A = 0^\circ\text{C}$ to 70°C , $V_{CC} = 5V \pm 5\%$ unless otherwise specified.

PARAMETER	TEST CONDITIONS	LIMITS			UNIT
		Min	Typ ¹	Max	
V_{IL} Input voltage Low V_{IH} High		-0.5 2.2		0.65 V_{CC}	V
V_{OL} Output voltage Low V_{OH} High	$I_{OL} = 1.9\text{mA}$ $I_{OH} = -100\mu\text{A}$	2.2		0.45	V
I_{LI} Input load current (All input pins)	$V_{IN} = 0$ to 5.25V			10	μA
I_{LOH} I_{LOL} Leakage current	$CE = 2.2\text{V}$ $V_{OUT} = 4.0\text{V}$ $V_{OUT} = 0.45\text{V}$			10 -100	μA
I_{CC1} I_{CC2} Supply current	All inputs = 5.25V , Data out open $T_A = 25^\circ\text{C}$ $T_A = 0^\circ\text{C}$		30	60 70	mA

AC ELECTRICAL CHARACTERISTICS $T_A = 0^\circ\text{C}$ to 70°C , $V_{CC} = 5V \pm 5\%$ unless otherwise specified.

PARAMETER	TO	FROM	2102			2102-1			2102-2			UNIT
			Min	Typ	Max	Min	Typ	Max	Min	Typ	Max	
t_{RC} t_A t_{CO} READ CYCLE Read cycle Access time	Output	Chip enable	1,000		1,000 500	500		500 350	650		650 400	ns ns ns
t_{OH1} t_{OH2} Previous data valid with respect to Address Chip enable			50 0			50 0			50 0			ns
t_{WC} t_{WP} t_{WR} WRITE CYCLE Write cycle Write pulse width Write recovery time			1,000 750 50			500 300 50			650 400 50			ns ns ns
t_{AW} t_{DW} t_{DH} t_{CW} Setup and hold time Setup time Setup time Hold time Setup time	Write Rise of R/W Change of data in Write	Address Data in Rise of R/W Chip enable	200 800 100			150 330 100			200 450 100			ns
			900			400			550			

NOTES

- Stresses above those listed under Absolute Maximum Ratings may cause permanent damage to the device. This is a stress rating only and functional operation of the device at these or any other condition above those indicated in the operation of the device of these or any other condition above those indicated in the operation sections of this specification is not implied.
- For operating at elevated temperatures the device must be derated based on a $+150^\circ\text{C}$ maximum junction temperature and a thermal resistance of $150^\circ\text{C}/\text{W}$ junction to ambient ("B" package).
- All inputs protected against static charge.
- Parameter valid over operating temperature range unless otherwise specified.
- All voltage measurements are referenced to ground.
- Manufacturer reserves the right to make design and process changes and improvements.
- Typical values are at $+25^\circ\text{C}$ and typical supply voltages.

TIMING DIAGRAMS

